



EMI TEST REPORT

Test Report No. : 10658078H-B

Applicant : Sharp Corporation, Communication Systems Division.
Type of Equipment : Cellular Phone
Model No. : SH-06G
FCC ID : APYHRO00219
Test standard : FCC Part 15 Subpart B 2015 Class B
Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
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6. This test report covers EMC technical requirements. It does not cover administrative issues such as Manual or non-EMC test related Requirements. (if applicable)

Date of test: March 17, 2015

**Representative
test engineer:**

T. Shimada

Takumi Shimada
Engineer
Consumer Technology Division

Approved by :

T. Hataheda

Takahiro Hataheda
Leader
Consumer Technology Division



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.
*As for the range of Accreditation in NVLAP, you may refer to the WEB address,
<http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

UL Japan, Inc.

Ise EMC Lab.

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13-EM-F0429

REVISION HISTORY

Original Test Report No.: 10658078H-B

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SECTION 1: Customer information

Company Name : Sharp Corporation, Communication Systems Division.
Address : 2-13-1 Iida Hachihonmatsu HigashiHiroshima-City, Hiroshima, 739-0192
Japan
Telephone Number : +81-82-420-1552
Facsimile Number : +81-82-420-1555
Contact Person : Hachiro Hidaka

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Cellular Phone
Model No. : SH-06G
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : March 17, 2015
Country of Mass-production : China
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product description

Feature of EUT : SH-06G is Quad-band W-CDMA(FDD1/5/6/19) Cellular Phone.
The EUT has the function that Bluetooth wireless technology interface.
Clock frequencies in the system : CPU: 1,200MHz (max)
Source oscillation: 19.2MHz(CPU), 27.0MHz(DTV)

SECTION 3: Test specification, procedures & results

3.1 Test specification

Test specification : FCC Part 15 Subpart B: 2015, final revised on January 21, 2015

Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	ANSI C63.4: 2009 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 4.8dB 0.16845MHz, L [AV] 7.0dB 0.16845MHz, L	Complied
Radiated emission	ANSI C63.4: 2009 8. Radiated emission measurements	Class B	N/A	5.1dB 797.535MHz, Horizontal, QP	Complied

*Note: UL Japan, Inc's EMI Work Procedure 13-EM-W0420.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (+dB)
	150kHz-30MHz
No.1	3.5dB
No.2	3.5dB
No.3	3.4dB
No.4	3.5dB

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	4.3dB	5.5dB	6.3dB	5.5dB	5.8dB	5.8dB	4.3dB
No.2	4.2dB	5.4dB	6.3dB	5.4dB	5.7dB	5.9dB	5.6dB
No.3	4.4dB	5.4dB	6.4dB	5.2dB	5.5dB	5.8dB	5.5dB
No.4	4.7dB	5.6dB	6.4dB	5.3dB	5.7dB	5.9dB	5.5dB

*3m/1m/0.5m = Measurement distance

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

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3.5 Test Location

UL Japan, Inc. Ise EMC Lab. *NVLAP Lab. code: 200572-0
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN
Telephone : +81 596 24 8999 Facsimile : +81 596 24 8124

	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	4.0 x 4.5 x 2.7m	4.0 x 4.5 m	-
No.6 measurement room	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	8.8 x 4.6 x 2.8m	2.4 x 2.4m	-
No.11 measurement room	-	6.2 x 4.7 x 3.0m	4.8 x 4.6m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test data, Test instruments, and Test set up

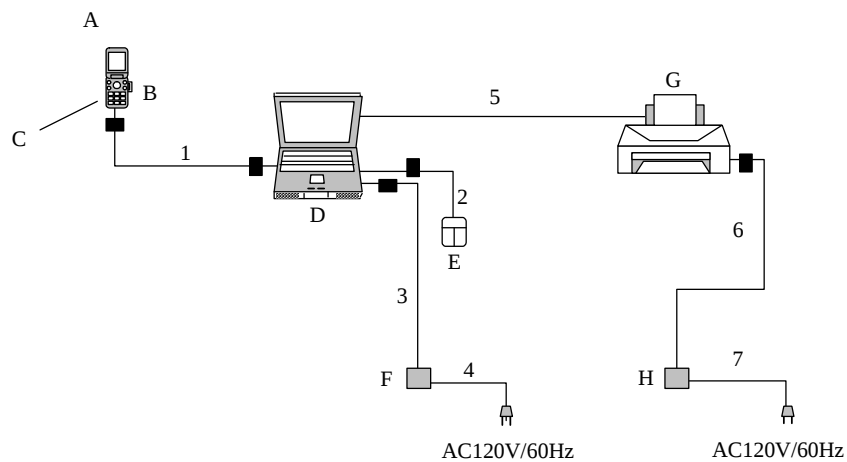
Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating modes

The mode(s) : 1) USB Data Com Mode
The USB data is communicated between EUT and Personal computer (Pair of EUT).
2) Standby Mode
Standby state for USB communication.

4.2 Configuration and peripherals



■ : Ferrite core which has been standard on support equipment.

*Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Cellular Phone	SH-06G	0044401/11/537516/0	Sharp Corporation	EUT
B	microSD Memory Card	SD-C02G	None	TOSHIBA	-
C	Lithium-Ion Battery	SH43	YBA	Sharp Corporation	EUT
D	Personal Computer	PP11L	CN-0D4571-48643-58P-1053	Dell	-
E	Mouse	M-UAG120	LZ733B70EVV	TOSHIBA	-
F	AC Adapter(PC)	LA65NS1-00	CN-0YD637-71615-64Q-2243	Dell	-
G	Printer	895Cxi	SG8BA1W18J	Hewlett Packard	-
H	AC Adapter(Printer)	C4557-60004	C8L01B	Hewlett Packard	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	USB Data Cable	1.20	Shielded	Shielded	-
2	Mouse Cable	0.72	Unshielded	Unshielded	-
3	AC Adaptor Cable (PC)	1.76	Unshielded	Unshielded	-
4	AC Power Cable (PC)	1.20	Unshielded	Unshielded	-
5	Parallel Cable	1.65	Shielded	Shielded	-
6	AC Adapter Cable (printer)	2.00	Unshielded	Unshielded	-
7	AC Power Cable (printer)	1.75	Unshielded	Unshielded	-

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SECTION 5: Conducted Emission

5.1 Operating environment

Test place	: No. 1 semi anechoic chamber
Temperature	: See data
Humidity	: See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from the LISN/AMN. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment. Photographs of the set up are shown in Appendix 3.

Frequency range	: 0.15 MHz-30MHz
EUT position	: Table top
EUT operation mode	: See Clause 4.1

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type	: Quasi-Peak and CISPR AV
IF Bandwidth	: 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: March 17, 2015

Test engineer: Takumi Shimada

UL Japan, Inc.

Ise EMC Lab.

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Facsimile : +81 596 24 8124

SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No. 1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The EUT was set on the edge of the tabletop.
Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength. Photographs of the set up are shown in Appendix 3.

6.3 Test conditions

Frequency range : 30MHz-300MHz (Biconical antenna) / 300MHz-1000MHz (Logperiodic antenna)
1000MHz -10000MHz (Horn antenna)
Test distance : 3m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.
The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver.
The radiated emission measurements were made with the following detector function of the Test Receiver.

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Test Receiver
IF Bandwidth	QP: BW 120kHz	PK: BW 1MHz, CISPR AV: BW 1MHz

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

6.5 Test result

Summary of the test results: Pass

Date: March 17, 2015 Test engineer: Takumi Shimada, Ken Fujita

APPENDIX 1: Data of EMI test

Conducted Emission

DATA OF CONDUCTED EMISSION TEST

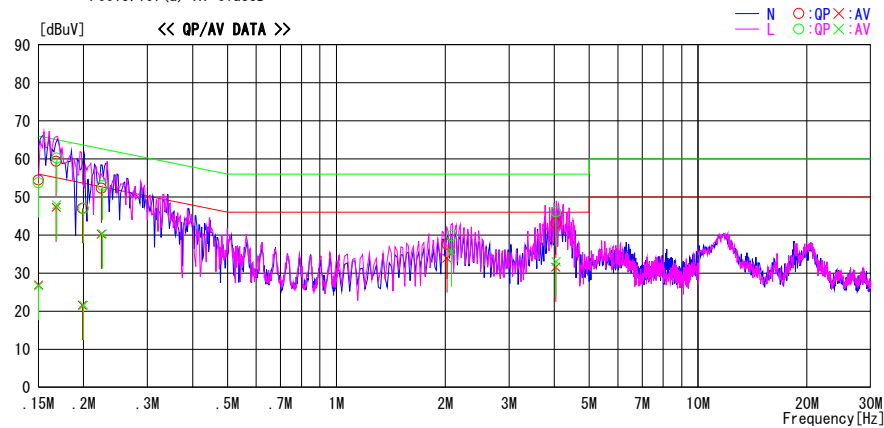
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/03/17

Report No. : 10658078H

Temp./Humi. : 20deg. C / 40% RH
Engineer : Takumi Shimada

Mode / Remarks : USB Data Com Mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15000	41.3	13.7	13.2	54.5	26.9	66.0	56.0	11.5	29.1	N	
0.16798	46.2	34.1	13.2	59.4	47.3	65.1	55.1	5.7	7.8	N	
0.19842	33.8	8.4	13.2	47.0	21.6	63.7	53.7	16.7	32.1	N	
0.22407	39.0	26.9	13.3	52.3	40.2	62.7	52.7	10.4	12.5	N	
2.02084	24.1	20.5	13.5	37.6	34.0	56.0	46.0	18.4	12.0	N	
4.04025	29.2	17.7	13.9	43.1	31.6	56.0	46.0	12.9	14.4	N	
0.15000	40.5	13.5	13.2	53.7	26.7	66.0	56.0	12.3	29.3	L	
0.16845	47.0	34.8	13.2	60.2	48.0	65.0	55.0	4.8	7.0	L	
0.19998	33.8	8.4	13.2	47.0	21.6	63.6	53.6	16.6	32.0	L	
0.22552	39.7	27.0	13.3	53.0	40.3	62.6	52.6	9.6	12.3	L	
2.07956	26.2	22.0	13.6	39.8	35.6	56.0	46.0	16.2	10.4	L	
4.04654	32.2	19.2	13.9	46.1	33.1	56.0	46.0	9.9	12.9	L	

CHART : WITH FACTOR, Peak hold data. CALCULATION : RESULT = READING + C.F (LISN + ATTN + CABLE)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Below 1GHz)

DATA OF RADIATED EMISSION TEST

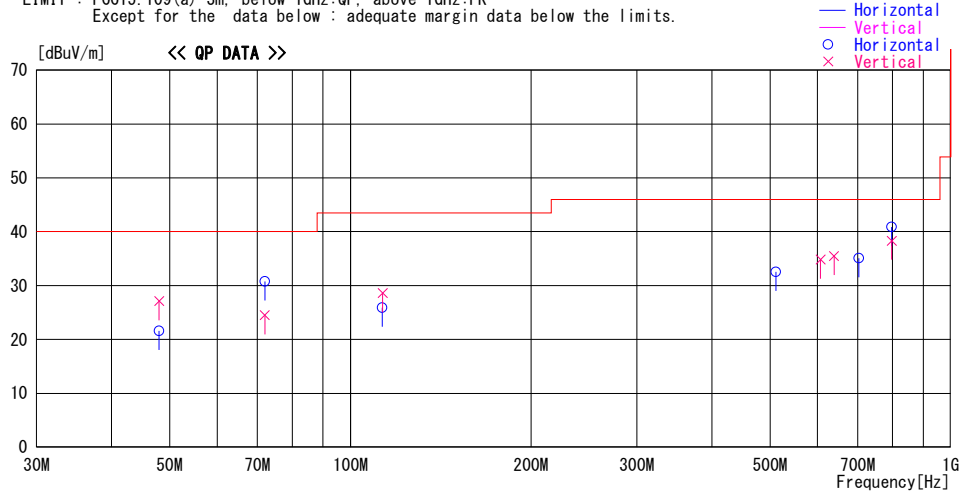
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/03/17

Report No. : 10658078H

Temp./Humi. : 20deg.C / 40% RH
Engineer : Ken Fujita

Mode / Remarks : USB Data Com Mode Worst axis (Hori X, Vert X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
48.028	41.4	QP	11.4	-31.2	21.6	104	266	Hori.	40.0	18.4	
48.017	46.9	QP	11.4	-31.2	27.1	68	100	Vert.	40.0	12.9	
72.024	55.2	QP	6.4	-30.8	30.8	107	262	Hori.	40.0	9.2	
72.027	48.9	QP	6.4	-30.8	24.5	38	215	Vert.	40.0	15.5	
113.200	46.9	QP	11.9	-30.2	28.6	8	100	Vert.	43.5	14.9	
112.960	44.3	QP	11.8	-30.2	25.9	171	152	Hori.	43.5	17.6	
511.270	40.4	QP	18.2	-26.1	32.5	48	194	Hori.	46.0	13.5	
607.131	40.9	QP	19.5	-25.6	34.8	347	100	Vert.	46.0	11.2	
639.086	41.0	QP	19.9	-25.4	35.5	350	100	Vert.	46.0	10.5	
703.003	39.7	QP	20.5	-25.1	35.1	142	100	Hori.	46.0	10.9	
797.605	41.1	QP	21.7	-24.5	38.3	68	100	Vert.	46.0	7.7	
797.535	43.7	QP	21.7	-24.5	40.9	145	100	Hori.	46.0	5.1	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE + ATTEN - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Below 1GHz)

DATA OF RADIATED EMISSION TEST

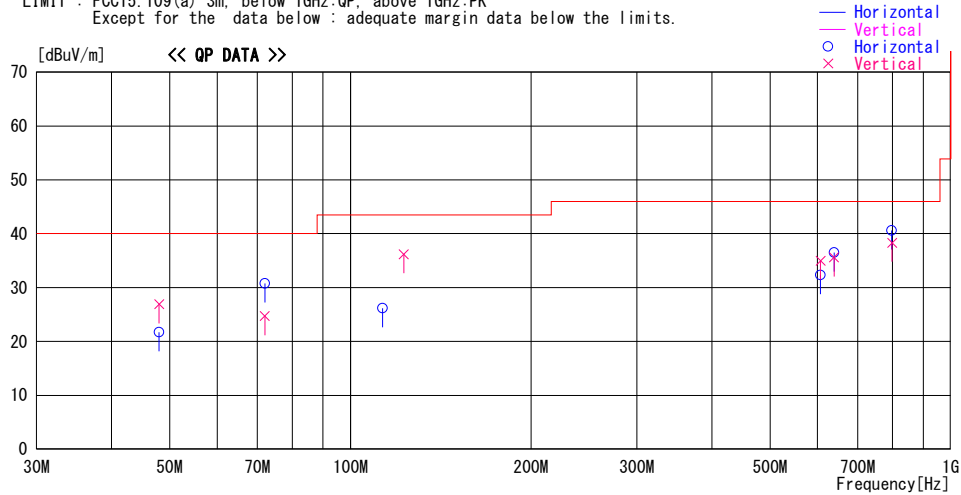
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/03/17

Report No. : 10658078H

Temp./Humi. : 20deg.C / 40% RH
Engineer : Ken Fujita

Mode / Remarks : Standby Mode Worst axis (Hori X, Vert X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
48.020	41.5	QP	11.4	-31.2	21.7	103	270	Hori.	40.0	18.3	
48.012	46.7	QP	11.4	-31.2	26.9	80	100	Vert.	40.0	13.1	
72.023	55.2	QP	6.4	-30.8	30.8	107	254	Hori.	40.0	9.2	
72.027	49.1	QP	6.4	-30.8	24.7	43	218	Vert.	40.0	15.3	
113.073	44.5	QP	11.9	-30.2	26.2	161	158	Hori.	43.5	17.3	
122.700	53.3	QP	13.0	-30.1	36.2	208	100	Vert.	43.5	7.3	
607.135	38.4	QP	19.5	-25.6	32.3	156	254	Hori.	46.0	13.7	
607.135	41.1	QP	19.5	-25.6	35.0	345	100	Vert.	46.0	11.0	
639.085	42.0	QP	19.9	-25.4	36.5	151	118	Hori.	46.0	9.5	
639.088	41.1	QP	19.9	-25.4	35.6	351	100	Vert.	46.0	10.4	
797.720	43.4	QP	21.7	-24.5	40.6	146	100	Hori.	46.0	5.4	
798.630	41.1	QP	21.7	-24.5	38.3	69	100	Vert.	46.0	7.7	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE + ATTEN - GAIN(AMP))

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*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Above 1GHz)

DATA OF RADIATED EMISSION TEST

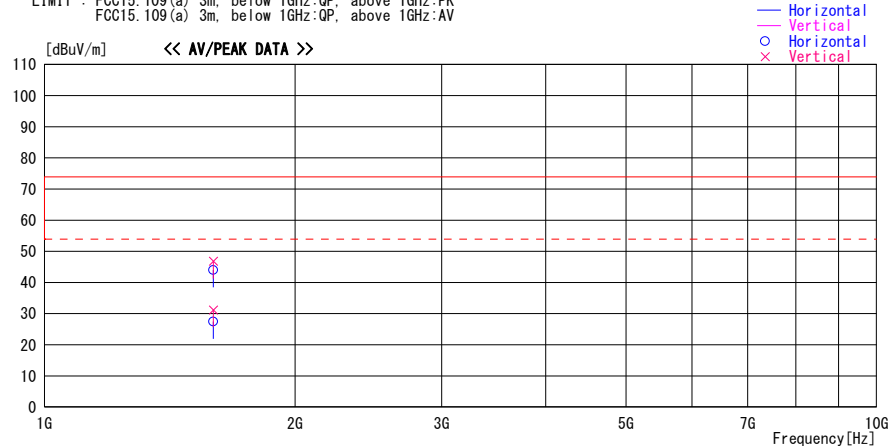
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Date : 2015/03/17

Report No. : 10658078H

Temp./Humi. : 20deg.C / 40% RH
Engineer : Takumi Shimada

Mode / Remarks : USB Data Com Mode Worst Axis (Hori X, Vert X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency	Reading	DET	Antenna	Loss&	Level	Angle	Height	Polar.	Limit	Margin	Comment
			Factor	Gain							
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
1595.710	52.9	PK	25.2	-34.1	44.0	314	100	Hori.	73.9	29.9	
1595.710	55.7	PK	25.2	-34.1	46.8	350	200	Vert.	73.9	27.1	
1595.710	36.4	AV	25.2	-34.1	27.5	314	100	Hori.	53.9	26.4	
1595.710	40.1	AV	25.2	-34.1	31.2	350	200	Vert.	53.9	22.7	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP. 30-300MHz:BICONICAL. 300MHz-1000MHz:LOGPERIODIC. 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Above 1GHz)

DATA OF RADIATED EMISSION TEST

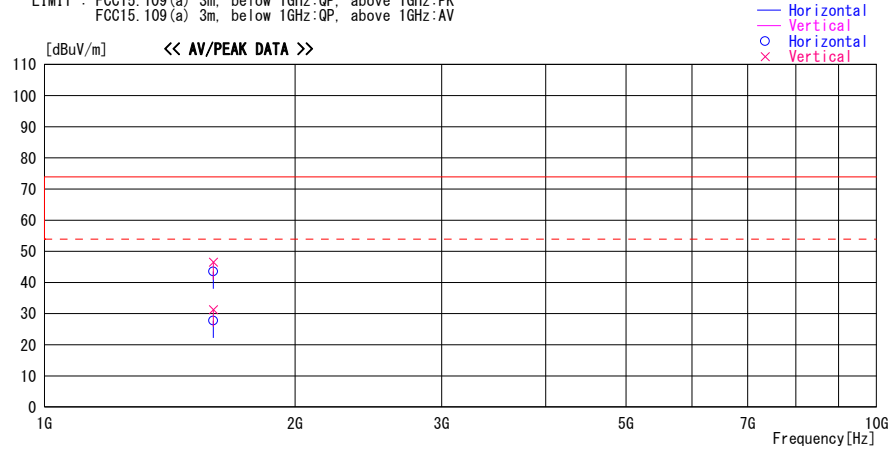
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/03/17

Report No. : 10658078H

Temp./Humi. : 20deg.C / 40% RH
Engineer : Takumi Shimada

Mode / Remarks : Standby Mode Worst Axis (Hori X, Vert X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency	Reading	DET	Antenna Factor	Loss& Gain	Level	Angle	Height	Polar.	Limit	Margin	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
1595.710	52.5	PK	25.2	-34.1	43.6	325	100	Hori.	73.9	30.3	
1595.710	55.4	PK	25.2	-34.1	46.5	359	150	Vert.	73.9	27.4	
1595.710	36.7	AV	25.2	-34.1	27.8	325	100	Hori.	53.9	26.1	
1595.710	40.2	AV	25.2	-34.1	31.3	359	150	Vert.	53.9	22.6	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

APPENDIX 2: Test instruments

EMI Test Instruments

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE/CE	2014/09/01 * 12
MOS-27	Thermo-Hygrometer	CUSTOM	CTH-201	A08Q26	RE/CE	2015/01/13 * 12
MJM-21	Measure	KOMELON	KMC-36	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MTR-09	EMI Test Receiver	Rohde & Schwarz	ESU26	100412	RE/CE	2014/06/06 * 12
KBA-05	Biconical Antenna	Schwarzbeck	BBA9106	2513	RE	2014/11/22 * 12
KLA-04	Logperiodic Antenna	Schwarzbeck	USLP9143	361	RE	2014/11/22 * 12
MAT-08	Attenuator(6dB)	Weinschel Corp	2	BK7971	RE	2014/11/20 * 12
MCC-02	Coaxial Cable	Suhner/storm/Agilent /TSJ	-	-	RE	2014/09/12 * 12
MPA-19	Pre Amplifier	MITEQ	MLA-10K01-B01-35	1237616	RE	2015/02/03 * 12
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2014/05/16 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2015/02/04 * 12
MCC-165	Microwave Cable	Junkosha	MWX221	1203S213(1m) / 1311S166(5m)	RE	2014/11/11 * 12
MLS-24	LISN(AMN)	Schwarzbeck	NSLK8127	8127-730	CE(EUT)	2014/07/10 * 12
MLS-26	LISN(AMN)	Schwarzbeck	NSLK8127	8127-732	CE(AE)	2014/07/09 * 12
MTA-28	Terminator	TME	CT-01	-	CE	2014/11/26 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/TSJ	5D-2W(20m)/ 3D-2W(7.5m)/ RG400u(1.5m)/ RFM-E421(Switcher)	-/01068 (Switcher)	CE	2014/09/12 * 12
MAT-64	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2015/01/29 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted Emissions

RE: Radiated Emissions

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